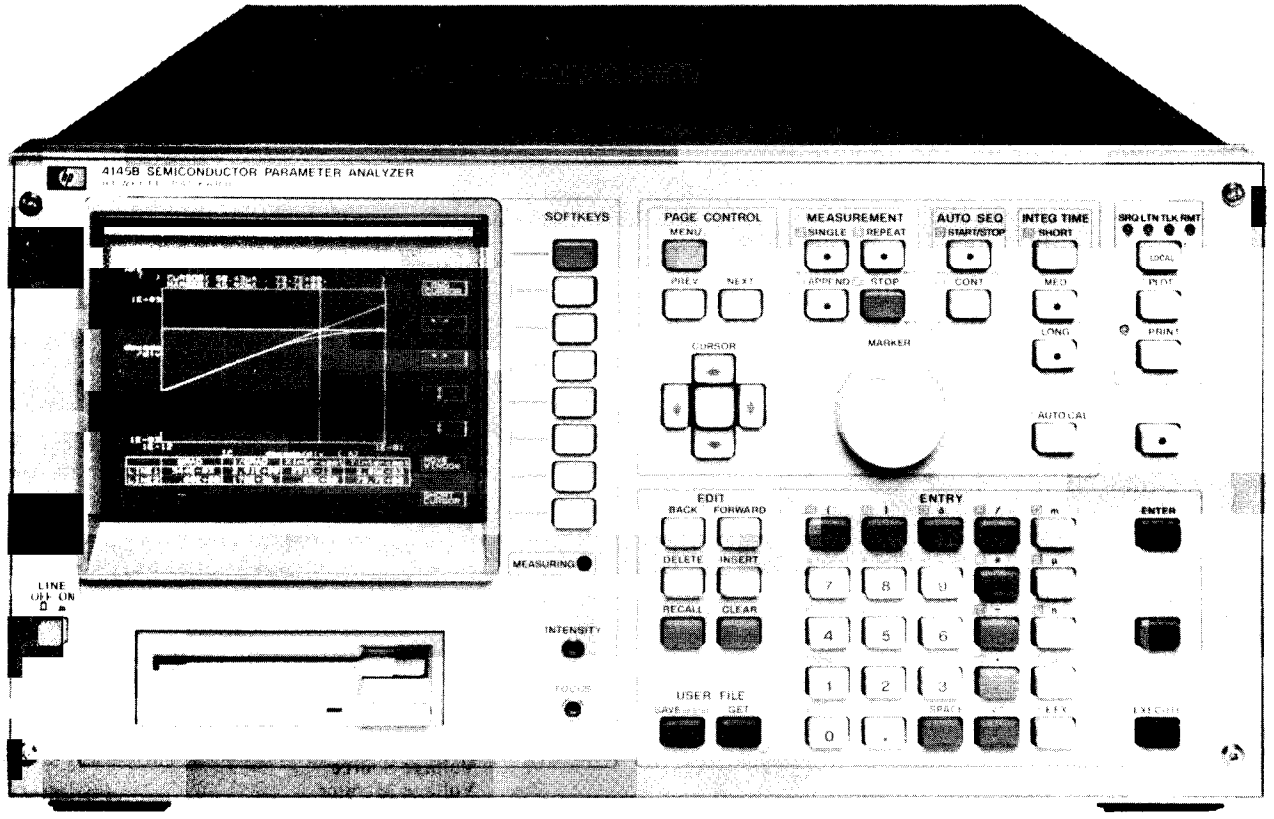
SEMICONDUCTOR TEST EQUIPMENT

Semiconductor Parameter Analyzer

Model 4145B

- Fully automatic, high-speed dc characterization of semiconductor devices.
- High resolution, wide range sourcing and measurement.
  I: 50fA – 100mA, V: 1mV – 100V
- Maximum 1150 measurement and display points for precise measurement and analysis.
- Flexible graphic analysis functions for quick parameter extraction.
- Built-in micro flexible disc drive for storage of 240 user programs or 105 measurement results.



HP 4145B

DESIGNED FOR HP-IB SYSTEMS

Description

Designed for production line and laboratory use, the HP 4145B is the electronics industry's first stand-alone instrument capable of complete dc characterization of semiconductor devices and materials. It stimulates voltage and current sensitive devices, measures the resulting current and voltage responses, and displays the results in a user-selectable format (graph, list, matrix or schmoo) on a built-in CRT display. An on-board programmable calculator provides real-time calculation of voltage/current dependent parameters, such as the current gain (h_{FE}) and transconductance(g_m) of transistors, which also can be displayed on the CRT. A number of powerful graphic analysis tools—marker, cursor, line function, interpolation—enhance the HP 4145B's basic capabilities and provide fast, accurate analysis of semiconductor devices, leading to increased production yields and improved device quality.

Four built-in source monitor units (SMUs) are the heart of the HP 4145B. Each SMU can be independently programmed to function as either a voltage source/current monitor or a current source/ voltage monitor. Thus, a bipolar transistor, for example, can be completely characterized in common-base, common-emitter, and common-collector configurations without changing connections—only changing the SMUs' operating modes is required. The HP 4145B is also equipped with two voltage sources and two voltage monitors for measurements on devices having more than four terminals, such as ICs.

The HP 4145B can be controlled from the front panel, via the HP-IB (standard), or by measurement setups stored on micro flexible discs.

Displayed information—measurement setups, auto-sequence programs, measurement results—can be dumped directly onto an external graphics printer/plotter to obtain publication quality hard copies. Additionally, the built-in 3½" flexible disc drive enables you to store measurement setups and measured data, which can be accessed by another compatible HP disc drive for further processing.

Auto Sequence Programs

Measurement programs stored on a HP 4145B micro flexible disc can be linked by an auto sequence program, making it possible to perform a series of measurements with just one keystroke.

Four User-Selectable Display Formats to Suit the Evaluation

Measurement results can be displayed in one of four display formats: GRAPHICS, LIST, MATRIX or SCHMOO. After measurement has been made and the results displayed, the softkeys can be used to access various analysis functions for complete device evaluation. These functions include MARKER for numeric readout of measured value at any point along a plotted curve, CURSOR for numeric readout of value at any graphic point and for line positioning, STORE /RECALL for overlay comparisons, AUTO SCALE for optimum graphic scaling, and LINE FUNCTION for direct readout of line gradient and X-Y axes intercept values.

Specifications

Measurement

Source/Monitor unit (SMU): four SMUs are built into the HP 4145B. Each SMU can be programmed to source voltage and monitor current, or conversely to source current and monitor voltage. Each SMU can also be programmed to COM mode. This sets voltage at 0 volts and current compliance at 105 mA.

Output/measurement resolution: voltage, 4½ digits; current, 4 digits

Voltage measurement input resistance/current source output resistance: $\geq 10^{12}\Omega$

Maximum capacitive load: 1000 pF

SMU Voltage Range, Resolution and Accuracy

Voltage Range	Resolution	Accuracy[1,2]	Max. Current
±20V	1mV	±(0.1%+10mV+0.4×Io)	100mA
±40V	2mV	±(0.1%+20mV+0.4×Io)	50mA
±100V	5mV	±(0.1%+50mV+0.4×Io)	20mA

*I_{o-v} is SMU output current in amps.

SMU Current Range, Resolution and Accuracy

Current Range	Resolution	Accuracy[1,2]	Max. Voltage
±100mA	100μA	±(0.3%+100μA+2μA×Vo)	20V(>50mA) 40V(>20mA)
±10mA	10μA	±(0.3%+10μA+200nA×Vo)	100V(≦20mA)
±1000μA	1μA	±(0.3%+1μA+20nA×Vo)	
±100μA	100nA	±(0.3%+100nA+2nA×Vo)	
±10μA	10nA	±(0.3%+10nA+200pA×Vo)	
±1000nA	1nA	±(0.5%+1nA+20pA×Vo)	
±100nA	100pA	±(0.5%+100pA+2pA×Vo)	
±10nA	10pA	±(1%+15pA+200fA×Vo)	
±1000pA	1pA	±(1%+6pA+20fA×Vo)	

*V_{o-v} is SMU output voltage in volts.
**50 fA resolution in current monitor mode.

1. Accuracy specifications are given as ±% of reading or setting value ±% of range.
2. Accuracy tolerances are specified at 25°C ±5°C, after a 40 minute warm-up time, with AUTO CAL on, and specified at the rear panel connector terminals referenced to SMU common. Tolerances are doubled for the extended temperature range of 10°C to 40°C.

SMU Voltage/Current Compliance

Maximum voltage compliance: 20 V, 40 V, or 100 V, depending on the output current range.

Maximum current compliance: 20 mA, 50 mA, or 100 mA, depending on the output voltage range.

Compliance setting resolution: same as current and voltage output/measurement resolution. Maximum current compliance resolution, however, is 50 pA.

Compliance accuracy: voltage compliance accuracy is the same as voltage output/measurement accuracy. Current compliance accuracy is current output/measurement accuracy ± (1% of range + 10 pA).

Voltage/Current Sweep Characteristics

Output from up to three SMUs or voltage sources can be swept in one of three modes: VAR1, VAR2, or VAR1′.

VAR1: linear or logarithmic staircase sweep

VAR2: linear staircase sweep. Output from the VAR2 source is incremented after completion of each VAR1 sweep.

VAR1′: output from the VAR1′ source is synchronized with VAR1 but at levels proportional to a user-selectable ratio or offset relative to VAR1.

Ratio: ±0.01 to ±10

Offset: any value that will not cause VAR1′ to exceed maximum allowable output.

Hold time: 0 to 650 seconds, ±(0.5% + 9 ms) with 10 ms resolution

Delay time: 0 to 6.5 seconds, ±(0.1% + 5 ms) with 1 ms resolution

No. of Measurement Steps: 1024 for a single VAR 1 sweep, 1150 for a multiple sweep

Voltage Sources (Vs) Characteristics

Number of sources: two

Output resistance: ≤0.2 Ω

Maximum capacitive load: 1000 pF

Voltage Output Range, Resolution and Accuracy

Output Voltage Range	Resolution	Accuracy	Max. Output Current
±20 V	1 mV	±(0.5% of setting + 10 mV)	10 mA

Voltage Monitors (Vm) Characteristics

Number of monitors: two

Input resistance: 1 MΩ ± 1% shunted by 100 pF ± 10%

Voltage Measurement Range, Resolution and Accuracy

Measurement Voltage Range	Resolution	Accuracy
± 2 V	100 μV	±(0.5% of reading + 10 mV)
±20 V	1 mV	±(0.2% of reading + 10 mV)

Characteristics Common to SMUs, Voltage Sources & Voltage Monitors

Maximum allowable terminal voltage: 100 V peak across SMU and V_m input terminals, or SMU and V_S output terminals, or between those terminals and guard; and 42 V maximum from Common to Ground.

Display

CRT size and screen resolution: 152.4 mm (6 inch) diagonal; 2048 x 2048 points.

Display modes: Graphics, Schmoo, List, Matrix, and Time Domain

External CRT analog output: X, Y and Z outputs of 0 to 1 Vdc into 330 Ω (X and Y) and 240 Ω (Z).

Analysis

Calculation: two user functions can be input and keyboard calculations can be done using the following 11 operators: +, –, *, /, $\sqrt{\ }$, EXP, LOG, LN, ** (power), ABS (absolute) and Δ (differential).

Constants Available on the Keyboard

q: Electron charge (1.602189×10^{-19} coulomb)
k: Boltzmann's Constant (1.380662×10^{-23} J/°K)
e: Dielectric constant of vacuum (8.854185×10^{-12} F/m)

Analysis functions: overlay comparison with STORE/RECALL, Marker, Interpolate, Cursor, Auto scale, Zoom function (←→, →←, ↑ ↓ Line and Move Window. ↓ ↑)

General Specifications

Operating temperature range: +10°C to +40°C; ≤70% RH at 40°C, permissible temperature change ≤1°C/5 min.

Power requirements: 100/120/220 V ± 10%; 240 V – 10% + 5%; 48 to 66 Hz; 270 VA max.

Dimensions: 426 mm W x 235 mm H x 612 mm D (16.75″ x 9.06″ x 24.1″).

Weight: 27 kg (59 lb) approximately.

Reference Data

SMU measurement time: measurement time = response time + ranging time + integration time.

SMU Response Time

Current Range	Setup/Settling Time	SMU Wait Time
100 nA to 100 mA	2.7 ms	0.2 ms
1 nA and 10 nA		47.5 ms

Ranging time: varies from 4 ms to 74 ms

Integration time: SHORT, MED and LONG

	SHORT	MED	LONG
50 Hz	3.6 ms	20 ms	320 ms
60 Hz		16.7 ms	267 ms

Accessories Furnished

HP 16058A Test Fixture
HP 04145-61501 System Disc
HP 04145-60001 Connector Plate
HP 04145-61622 Triaxial Cable (3m), 4 ea.
HP 04145-61630 BNC Cable (3m), 4 ea.
HP 04145-61623 Shorting Connector

Ordering Information

HP 4145B Semiconductor Parameter Analyzer **$24,450**
Opt. 050/060: 50Hz/60Hz Line Frequency N/C